

Search Notes**Application/Control No.**

10/716,544

Examiner

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Applicant(s)/Patent under Reexamination

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Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
370	328	5/2-3/2007	FH
370	332	5/2-3/2007	FH
370	465	5/2-3/2007	FH
370	318	5/2-3/2007	FH
370	468	5/2-3/2007	FH
455	522	5/2-3/2007	FH
455	69	5/2-3/2007	FH
455	452.1	5/2-3/2007	FH
455	226.2	5/2-3/2007	FH
455	115.3	5/2-3/2007	FH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search: power, rate, measur\$3, calcualt\$3, determin\$3, sens\$3, adjust\$3, chang\$3, modify\$3, alter\$3, increas\$3, decreas\$3	5/2-3/2007	FH
Consulted Ian Moore	5/2/2007	FH